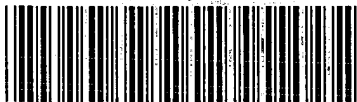


Search Notes

Application/Control No.

10/774,142

Examiner

CHAN S. PARK

Applicant(s)/Patent under
Reexamination

YOSHIDA ET AL.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	1.15-1.17	11/28/2007	CP
345	156	11/28/2007	CP
455	456.1	11/28/2007	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see the search history)	11/28/2007	CP